

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight on - Keypad open)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 824.7 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

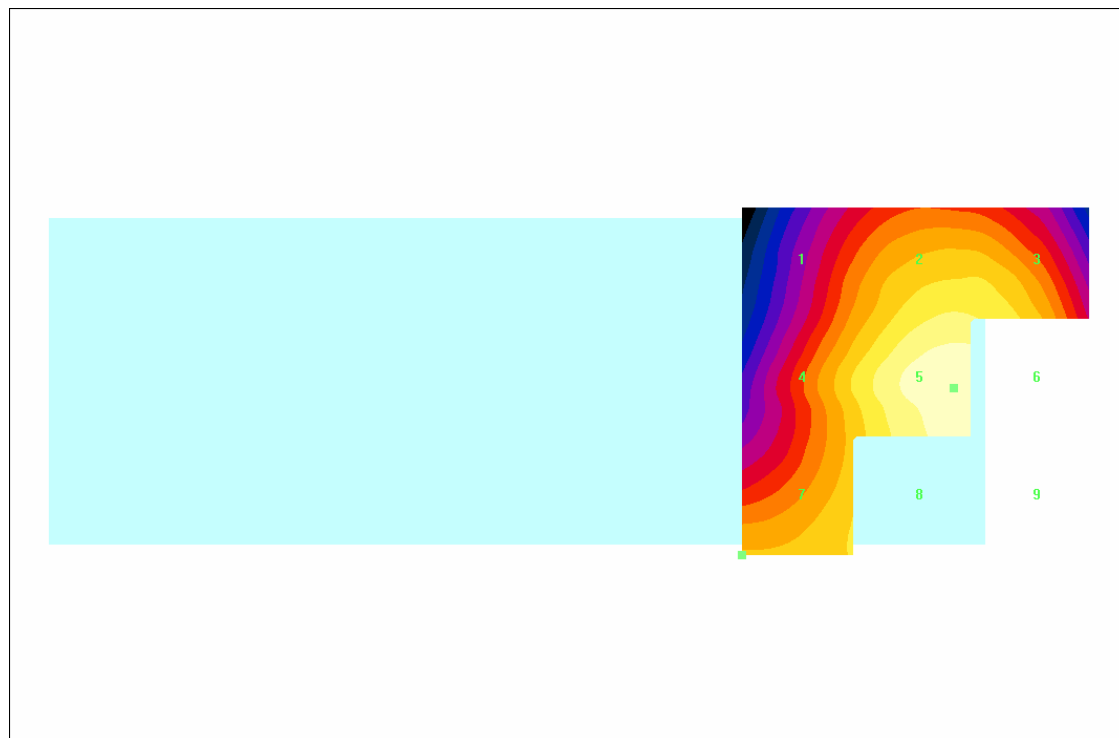
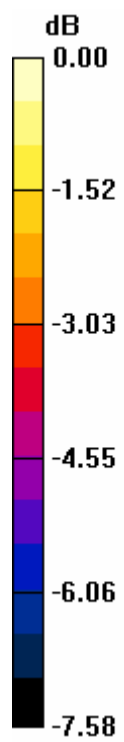
Maximum value of Total field (slot averaged) = 70.8 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 51.6	Grid 2 61.1	Grid 3 60.6	Grid 1 53.9	Grid 2 63.8	Grid 3 63.3
Grid 4 57.4	Grid 5 67.8	Grid 6 67.2	Grid 4 60.0	Grid 5 70.8	Grid 6 70.1
Grid 7 57.4	Grid 8 65.6	Grid 9 65.5	Grid 7 59.9	Grid 8 68.5	Grid 9 68.4

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 67.8V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight on - Keypad open)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 836.49 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

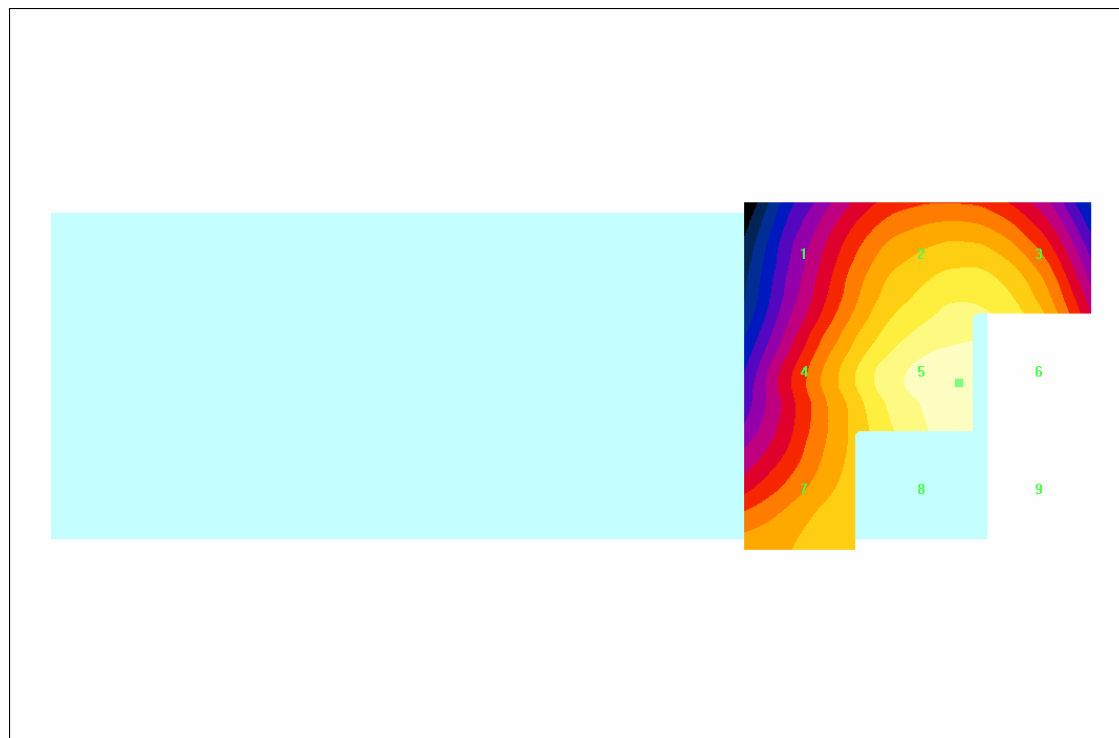
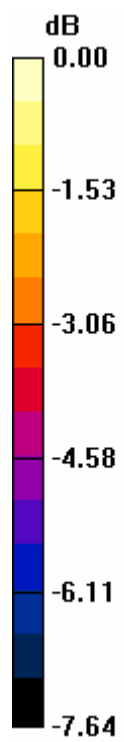
Maximum value of Total field (slot averaged) = 74.7 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 54.0	Grid 2 64.8	Grid 3 64.6	Grid 1 56.4	Grid 2 67.7	Grid 3 67.4
Grid 4 60.2	Grid 5 71.6	Grid 6 71.5	Grid 4 62.8	Grid 5 74.7	Grid 6 74.6
Grid 7 60.0	Grid 8 69.6	Grid 9 69.6	Grid 7 62.7	Grid 8 72.7	Grid 9 72.7

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 71.6V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight on - Keypad open)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 848.31 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

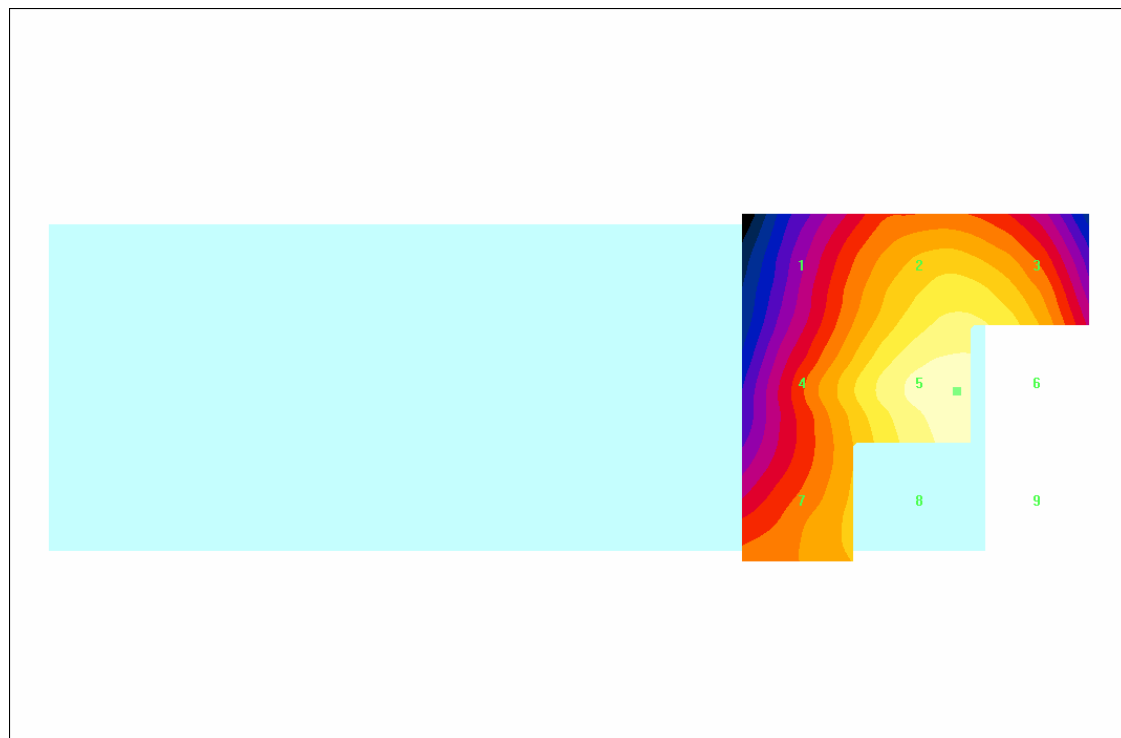
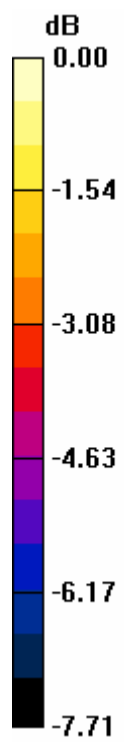
Maximum value of Total field (slot averaged) = 85.4 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 61.1	Grid 2 74.1	Grid 3 73.8	Grid 1 63.8	Grid 2 77.4	Grid 3 77.0
Grid 4 68.3	Grid 5 81.8	Grid 6 81.6	Grid 4 71.3	Grid 5 85.4	Grid 6 85.1
Grid 7 65.9	Grid 8 78.5	Grid 9 78.3	Grid 7 68.8	Grid 8 81.9	Grid 9 81.8

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 81.8V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight off - Keypad open)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 824.7 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

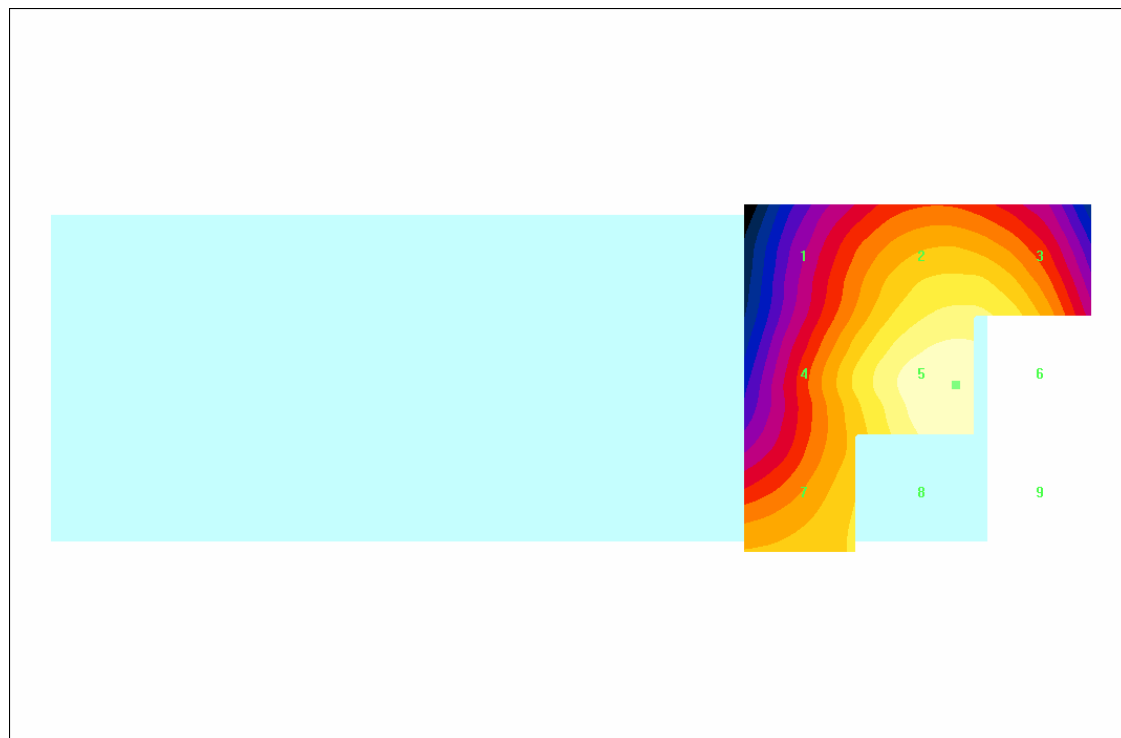
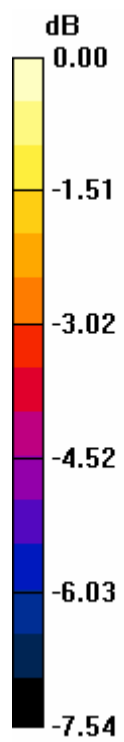
Maximum value of Total field (slot averaged) = 71.1 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 51.7	Grid 2 61.8	Grid 3 61.7	Grid 1 54.0	Grid 2 64.6	Grid 3 64.5
Grid 4 58.0	Grid 5 68.1	Grid 6 67.8	Grid 4 60.5	Grid 5 71.1	Grid 6 70.8
Grid 7 57.8	Grid 8 66.3	Grid 9 66.2	Grid 7 60.4	Grid 8 69.3	Grid 9 69.2

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 68.1V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight off - Keypad open)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 836.49 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

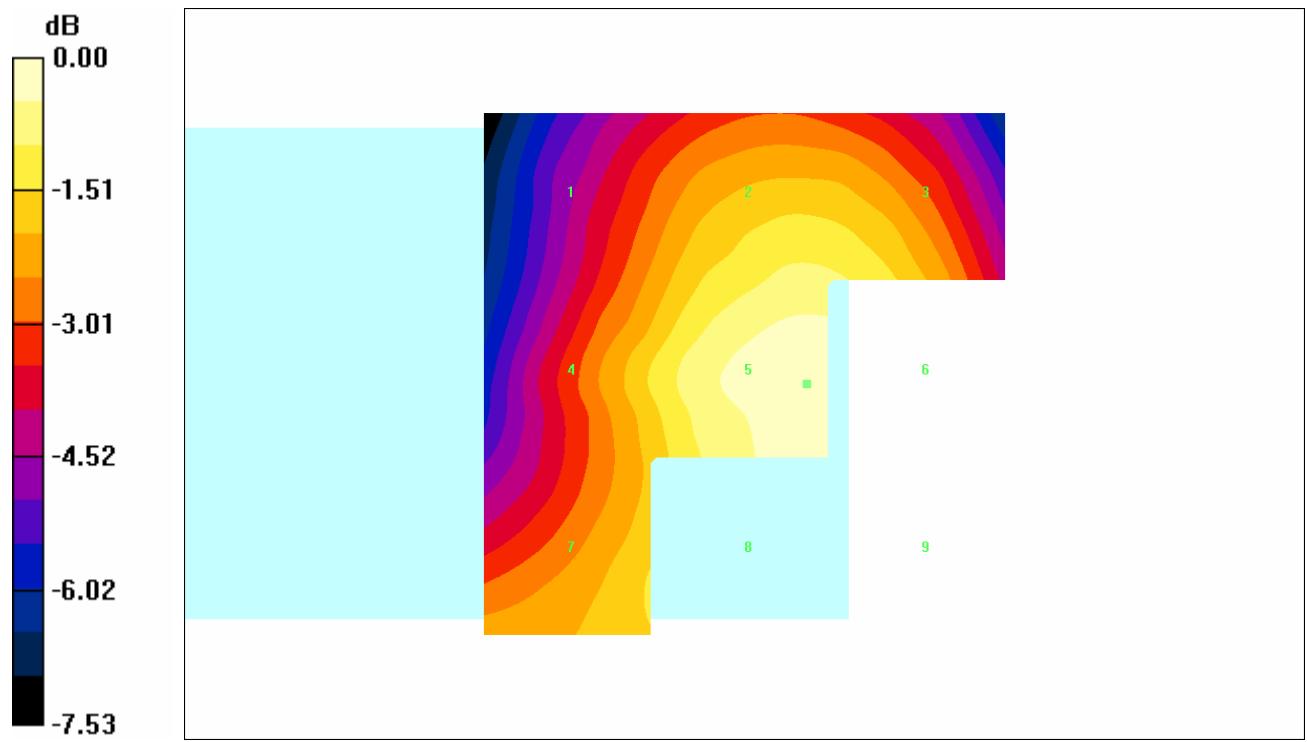
Maximum value of Total field (slot averaged) = 72.4 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 55.0	Grid 2 65.8	Grid 3 65.3	Grid 1 55.0	Grid 2 65.8	Grid 3 65.3
Grid 4 61.3	Grid 5 72.4	Grid 6 72.1	Grid 4 61.3	Grid 5 72.4	Grid 6 72.1
Grid 7 61.3	Grid 8 70.4	Grid 9 70.4	Grid 7 61.3	Grid 8 70.4	Grid 9 70.4

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 72.4V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight off - Keypad open)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 848.31 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

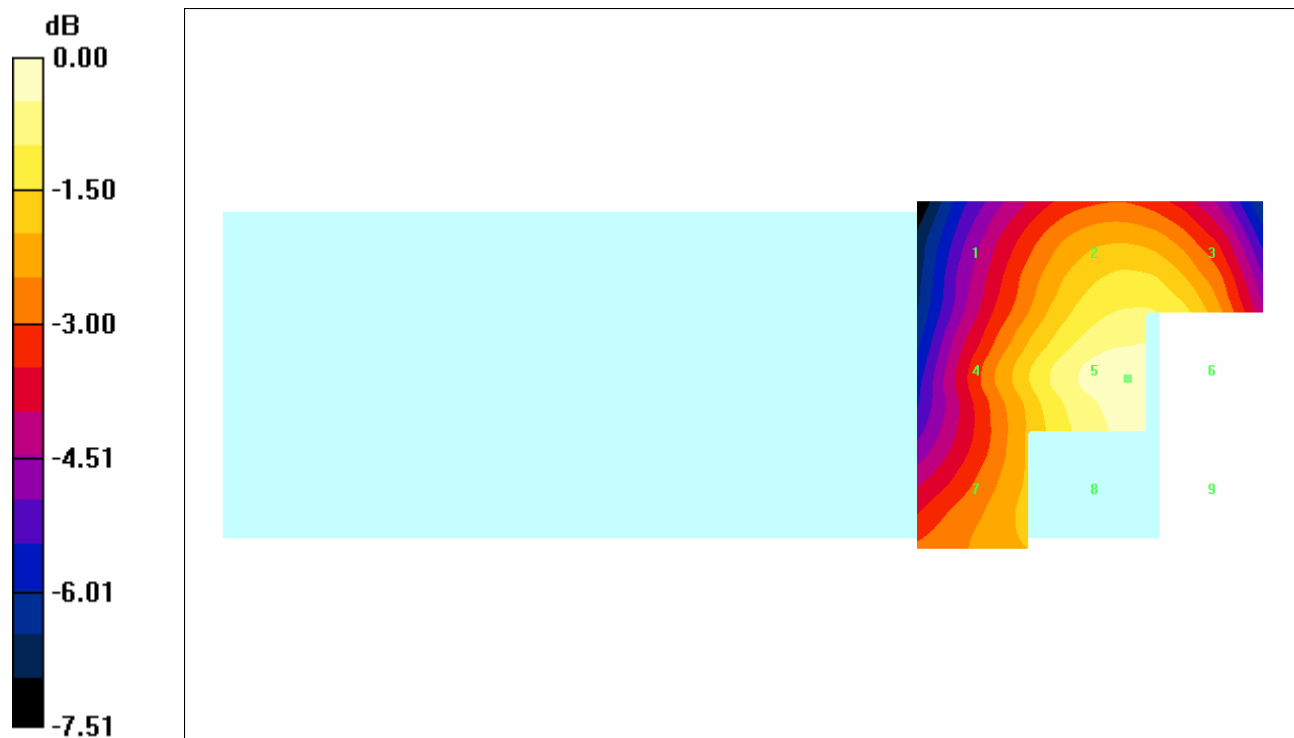
Maximum value of Total field (slot averaged) = 86.9 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 62.4	Grid 2 74.8	Grid 3 74.7	Grid 1 65.1	Grid 2 78.1	Grid 3 78.0
Grid 4 69.7	Grid 5 83.2	Grid 6 82.2	Grid 4 72.8	Grid 5 86.9	Grid 6 85.8
Grid 7 67.5	Grid 8 80.0	Grid 9 79.8	Grid 7 70.5	Grid 8 83.5	Grid 9 83.3

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 83.2V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 824.7 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

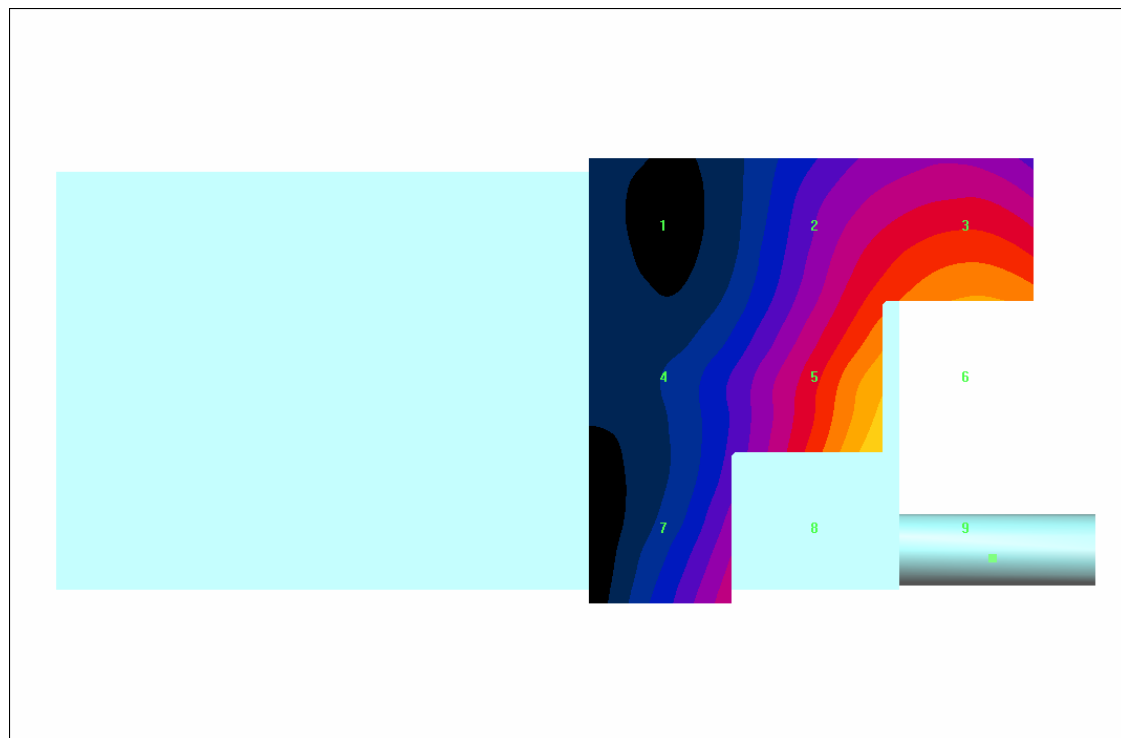
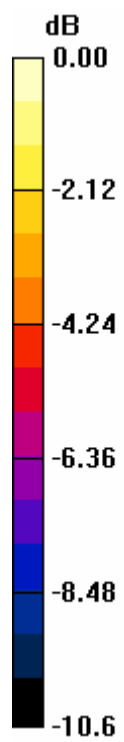
Maximum value of Total field (slot averaged) = 69.7 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 30.5	Grid 2 50.7	Grid 3 57.7	Grid 1 31.8	Grid 2 52.9	Grid 3 60.2
Grid 4 35.7	Grid 5 66.7	Grid 6 78.9	Grid 4 37.3	Grid 5 69.7	Grid 6 82.3
Grid 7 44.0	Grid 8 75.4	Grid 9 85.4	Grid 7 46.0	Grid 8 78.7	Grid 9 89.2

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 85.4V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 836.49 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

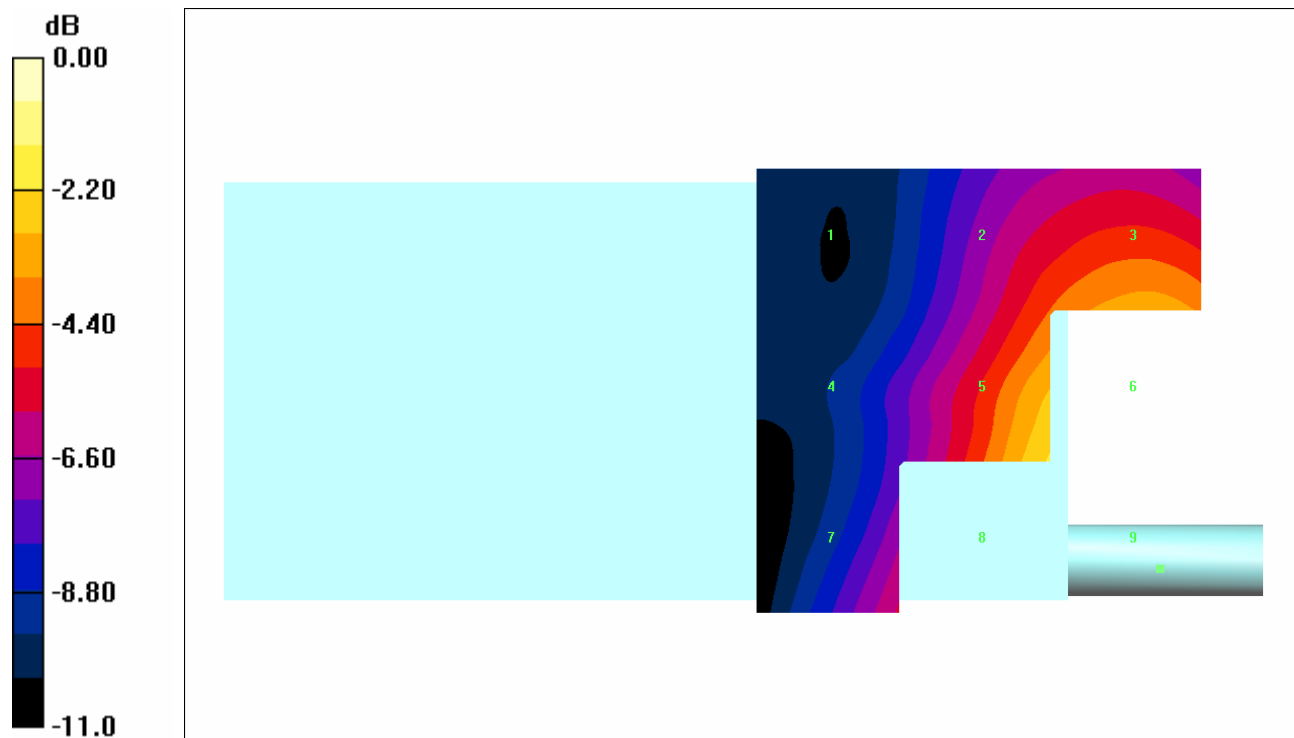
Maximum value of Total field (slot averaged) = 72.9 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 31.5	Grid 2 53.6	Grid 3 61.2	Grid 1 32.8	Grid 2 56.0	Grid 3 63.9
Grid 4 37.0	Grid 5 69.8	Grid 6 81.8	Grid 4 38.6	Grid 5 72.9	Grid 6 85.4
Grid 7 45.9	Grid 8 78.8	Grid 9 88.6	Grid 7 47.9	Grid 8 82.3	Grid 9 92.5

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 88.6V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight on - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 848.31 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

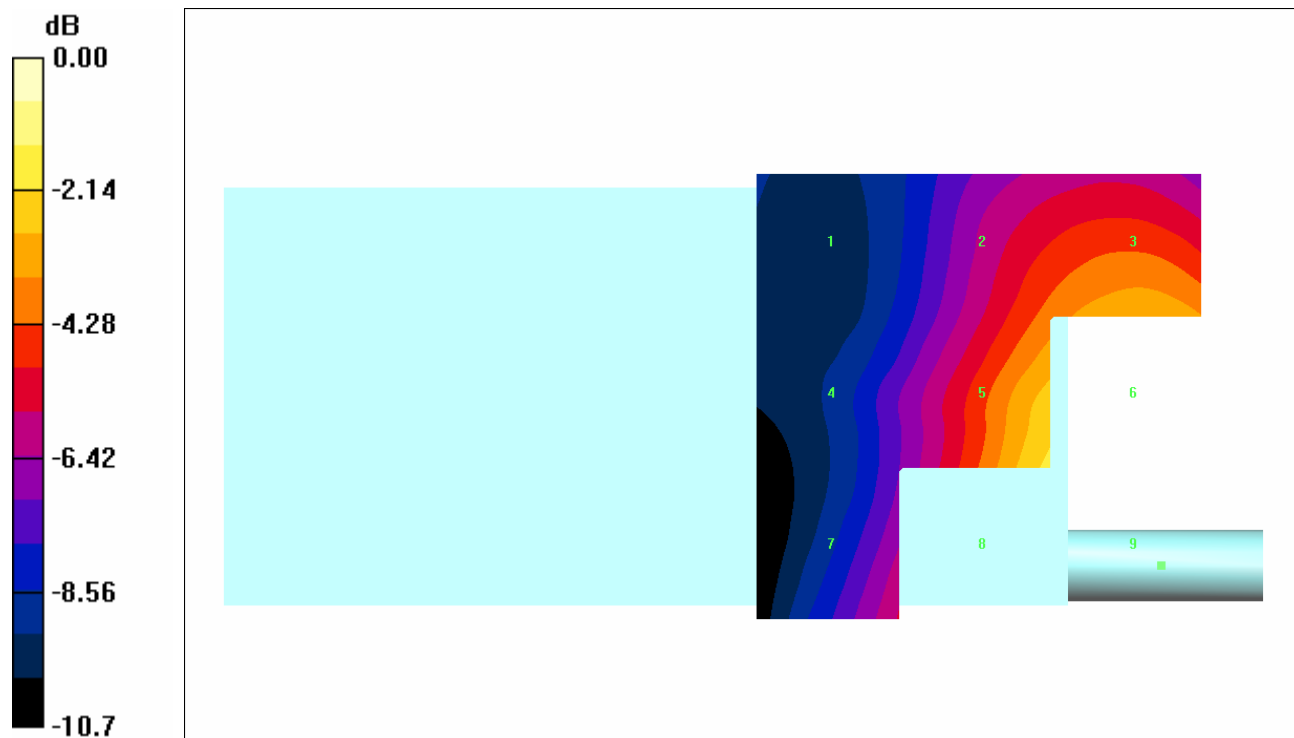
Maximum value of Total field (slot averaged) = 76.6 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 35.2	Grid 2 58.0	Grid 3 64.7	Grid 1 36.8	Grid 2 60.5	Grid 3 67.6
Grid 4 40.4	Grid 5 73.4	Grid 6 85.0	Grid 4 42.2	Grid 5 76.6	Grid 6 88.7
Grid 7 47.9	Grid 8 81.6	Grid 9 91.3	Grid 7 50.0	Grid 8 85.2	Grid 9 95.3

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight off - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 824.7 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

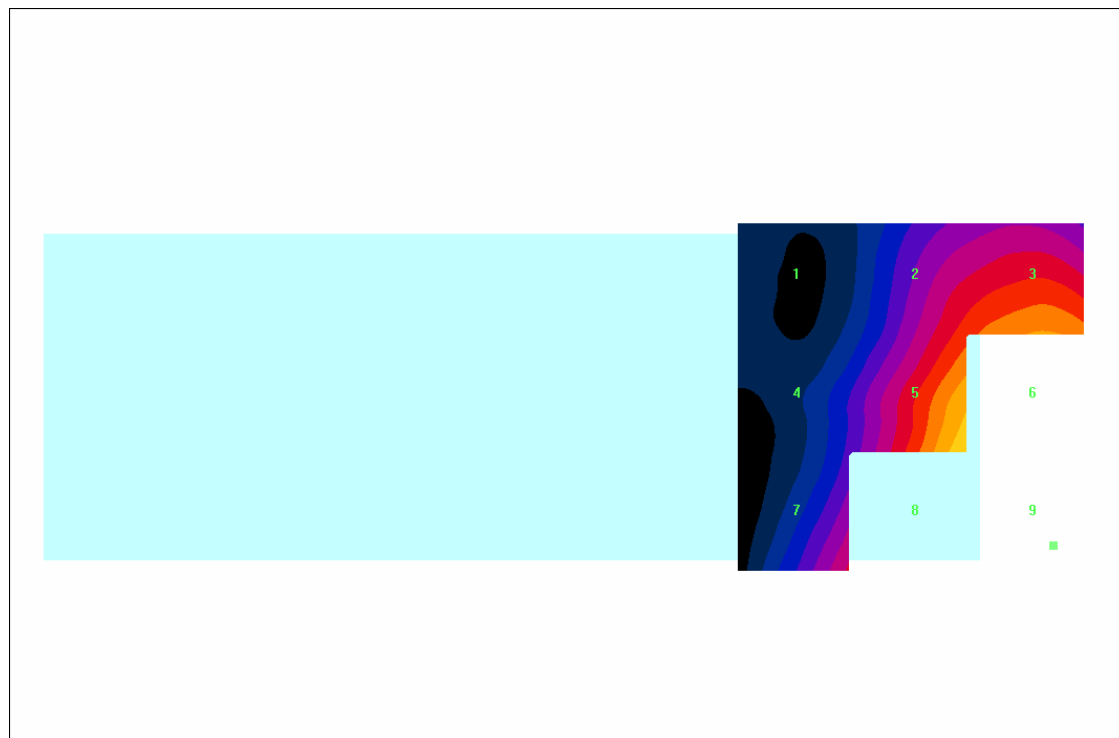
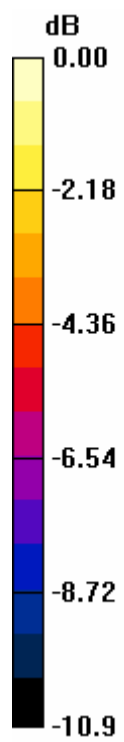
Maximum value of Total field (slot averaged) = 69.6 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 29.8	Grid 2 50.3	Grid 3 57.3	Grid 1 31.1	Grid 2 52.6	Grid 3 59.8
Grid 4 35.1	Grid 5 66.6	Grid 6 78.7	Grid 4 36.6	Grid 5 69.6	Grid 6 82.2
Grid 7 44.8	Grid 8 76.6	Grid 9 85.9	Grid 7 46.8	Grid 8 79.9	Grid 9 89.6

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 85.9V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight off - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 836.49 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DASY4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

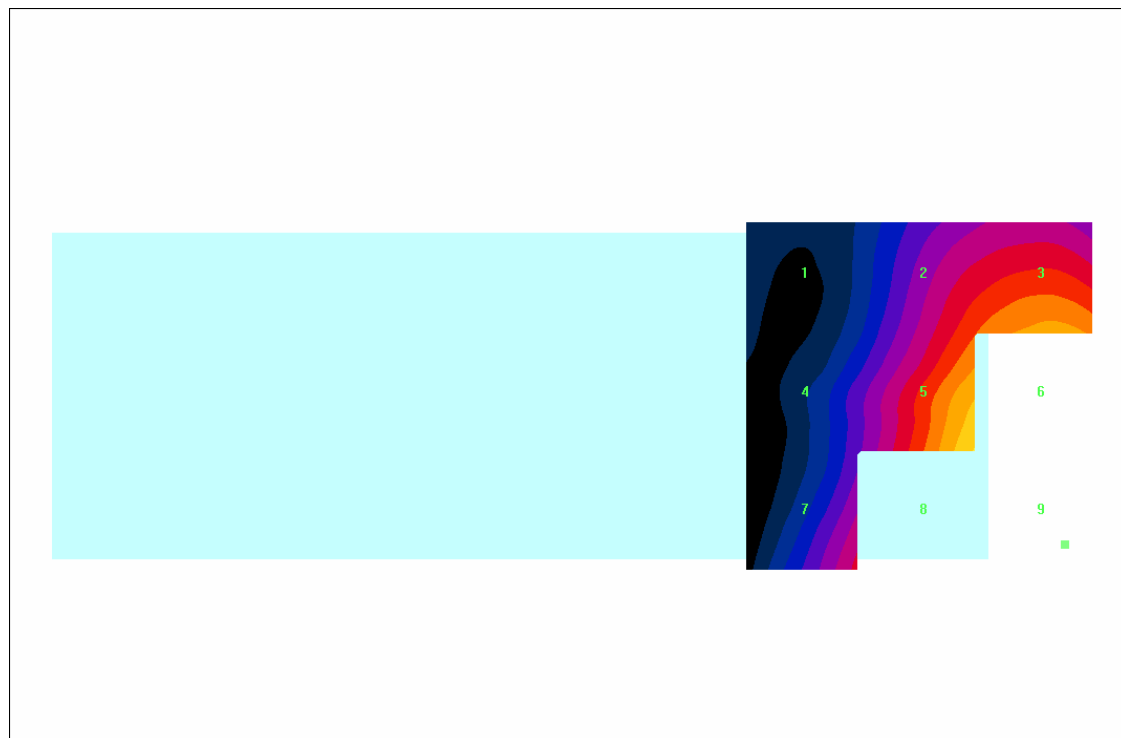
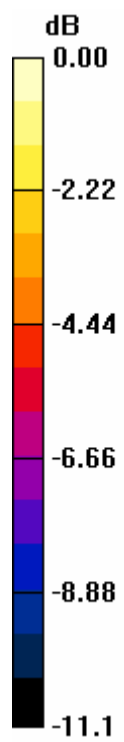
Maximum value of Total field (slot averaged) = 73.5 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 31.7	Grid 2 53.8	Grid 3 61.3	Grid 1 33.1	Grid 2 56.1	Grid 3 64.0
Grid 4 37.6	Grid 5 70.4	Grid 6 82.7	Grid 4 39.2	Grid 5 73.5	Grid 6 86.3
Grid 7 47.1	Grid 8 80.2	Grid 9 90.0	Grid 7 49.1	Grid 8 83.7	Grid 9 93.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 90.0V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band (Backlight off - Keypad close)

DUT: Kyocera; Type: KX5-5C1; Serial: 20-M7405-01

Communication System: CDMA Cellular band; Frequency: 848.31 MHz; Duty Cycle: 1:1.09

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan -H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

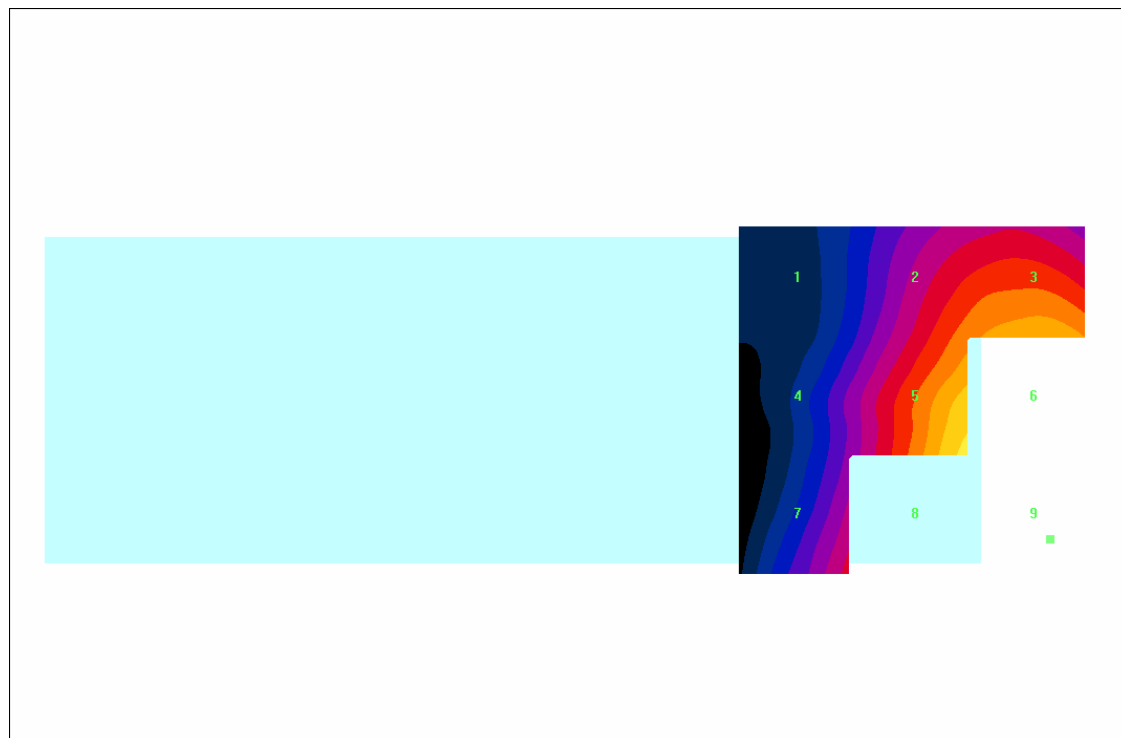
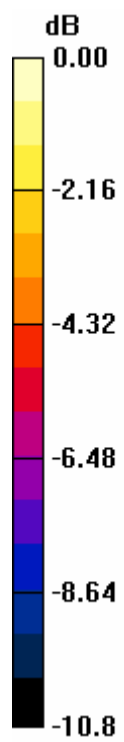
Maximum value of Total field (slot averaged) = 78.8 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 36.3	Grid 2 59.5	Grid 3 65.8	Grid 1 37.9	Grid 2 62.1	Grid 3 68.6
Grid 4 42.0	Grid 5 75.5	Grid 6 86.3	Grid 4 43.8	Grid 5 78.8	Grid 6 90.1
Grid 7 50.0	Grid 8 84.6	Grid 9 93.0	Grid 7 52.2	Grid 8 88.3	Grid 9 97.1

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 93.0V/m